

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10520151	KURITA, TADASHI
	Examiner	Art Unit
	GELEK TOPGYAL	2621

SEARCHED

Class	Subclass	Date	Examiner
386	46,65,66,95,98,102,109	3/13/2008	GT
348	565	2/15/2009	GT

SEARCH NOTES

Search Notes	Date	Examiner
Thai Tran: Determined any subsampling system used for PIP processing meets the claimed invention.	3/13/2008	GT
Researched	9/12/08	GT
See attached for Inventor and Interference search. Thai Tran determined allowability of claims.	1/17/2009	GT

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
386	46	2/15/2009	GT
348	565	2/15/2009	GT

/GELEK TOPGYAL/
Examiner Art Unit 2621